

A. INTERPRET DRAWING IN ACCORDANCE WITH STANDARDS PRESCRIBED BY MIL-D-70327. B. UNITS SHALL MEET THE REQUIREMENTS OF MIL-S-19500 EXCEPT AS, AND IN ADDITION TO, THE REQUIREMENTS SPECIFIED HEREIN.

(1) THE TESTS AS DEFINED IN TABLES I, II, AND III SHALL BE PERFORMED BY THE QUALITY CONTROL DEPARTMENT OF THE VENDOR. (2) UNLESS OTHERWISE SPECIFIED HEREIN ALL ELECTRICAL TESTS MUST BE REFERENCED TO AN AMBIENT TEMPERATURE OF PLUS 25

(3). THE PRE-SEAL TEST PER TABLE I SHALL BE PERFORMED AFTER THE FINAL PRODUCTION INTERNAL VISUAL INSPECTION AND

(1) DATA FROM TABLE I AND II SHALL ACCOMPANY THE LOT WHEN SHIPPED TO THE PURCHASER. UNITS USED IN QUALITY DEMONSTRATION TESTS OF TABLE III SHALL NOT BE SHIPPED AS PART OF THE DELIVERY BUT SHALL BE FORWARDED ALONG WITH THE TEST DATA FROM TABLE III UNDER SEPARATE COVER TO THE PURCHASER, ATTENTION: PURCHASING AGENT.

(2) THE DATA SUPPLIED PER TABLE I SHALL INCLUDE THE NUMBER OF SUB-LOTS TESTED, THE NUMBER OF UNITS THAT FAILED FROM EACH SUB-LOT, THE CAUSE OF FAILURE, AND THE NUMBER OF TIMES THE SUB-LOT WAS RE-SUBMITTED. THE MAXIMUM SIZE FOR

(3) THE DATA SUPPLIED PER TABLE II SHALL INCLUDE THE NUMBER OF UNITS REJECTED PER THE TEST, THE CAUSE OF REJECTION, AND

(4) THE DATA SUPPLIED PER TABLE III SHALL INCLUDE THE NUMBER OF UNITS REJECTED PER THE TEST, THE CAUSE FOR REJECTION BY SERIAL NUMBER AND THE DATE CODE OF THE UNITS.

(1) THE SAMPLE USED FOR TABLE II SHALL BE RANDOMLY SELECTED FROM THE ENTIRE GROUP OF UNITS WHICH CONSTITUTE A LOT. (2) A LOT MAY BE RESUBMITTED FOR TABLE II AND TABLEIL ONCE. THE REQUIREMENT OF MIL-S-1900c FOR LOT RESUBMITTAL SHALL APPLY WITH THE TIGHTENED INSPECTION FOR THE CHARACTERISTICS WHICH FAILED.

(3) UNITS USED IN TABLE III, SUBGROUPS 1 AND 5 MAY BE ELECTRICAL REJECTS FROM THE SAME LOT.

(4) ACCEPTABLE UNITS USED IN TESTING SUBGROUP 2 OF TABLE II SHALL BE USED IN SUBGROUPS 2, 3, AND 4 OF TABLE III. IN TABLE III ACCEPTABLE UNITS FROM SUBGROUP 2 MAY BE USED IN SUBGROUP 5.

(5) AFTER COMPLETION OF TESTS, UNITS USED IN SUBGROUP 3 OF TABLE III SHALL BE USED IN SUBGROUN



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NLESS OTHERWISE SPECIFIED MENSIONS ARE IN INCHES APACITOR VALUES ARE IN #f	· - IN	MIT STRUMENTATION CAMBRIDGE, MASS.	LAB		1	MANN	IE
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(1) UNITS SHALL BE DATE CODED INDICATING THE WEEK SEALING OPERATION WAS PERFORMED. AN ADDITIONAL LETTER MAY BE ADDED TO THE DATE CODE TO SEPARATE LOTS FOR THE PURPOSE OF TRACEABILITY.

(1) VOLTAGE TO PIN 10: PLUS 10.0 VOLTS WITH RESPECT TO PIN 5. (2) VOLTAGE APPLIED TO ANY INPUT PIN PLUS OR MINUS 4 VOLTS WITH RESPECT TO PIN 5. (3) THERMAL RESISTANCE, JUNCTION-CASE. (O<sub>JC</sub>): 200°C/WATT. THERMAL RESISTANCE, JUNCTION-AMBIENT. (OJA): 500°C/WATT.

(1) TEMPERATURE RANGE, JUNCTION, OPERATING: -55°C TO +125°C. (2) TEMPERATURE RANGE, JUNCTION, STORAGE: -65°C TO +150°C.

(3) TEMPERATURE, SOLDERING LEADS: +250°C (1 MINUTE MAX). (2) ENCLOSURE: SEE FIGURE, HERMETICALLY SEALED AND ELECTRICALLY ISOLATED FROM POWER OR GROUND.

LEAD MATERIAL SHALL BE IN ACCORDANCE WITH NASA DOCUMENT PS 1015402 WITH THE FOLLOWING EXCEPTIONS: GOLD PLATE SHALL BE A MINIMUM OF 100 AND A MAXIMUM OF 200 MICRO INCHES, THE NICKEL STRIKE UNDER THE GOLD SHALL BE OPTIONAL BUT IF USED SHALL BE A MAXIMUM OF 100 MICRO INCHES, AND PARAGRAPH 3.4.2. SHALL NOT APPLY. CERTIFICATE OF COMPLIANCE FOR LEAD MATERIAL SHALL ACCOMPANY EACH LOT SHIPPED.

A. LEAD FATIGUE: LEADS SHALL BE CAPABLE OF WITHSTANDING THE FOLLOWING LEAD BEND TEST. THE UNIT SHALL BE HELD IN A VERTICAL POSITION WITH A 2 OUNCE WEIGHT SUSPENDED FROM THE LEAD TO BE TESTED. TWO CYCLES OF BENDING SHALL BE PERFORMED. A CYCLE CONSISTING OF MOVING THE BODY OF THE UNIT, 45 DEGREES FROM THE VERTICAL IN ONE DIRECTION, AND BACK 45 DEGREES TO THE ORIGINAL POSITION. NO MECHANICAL DAMAGE SHALL BE EVIDENCED AFTER THE TEST.

B. LEAD TENSION: EACH LEAD SHALL BE CAPABLE OF WITHSTANDING AN AXIAL PULL OF 1 POUND MINIMUM FOR 30 SECONDS. NO MECHANICAL DAMAGE SHALL BE EVIDENCED AFTER THE TEST.

THE UNITS SHALL BE SUBJECTED TO THE LEAK TESTS AS SPECIFIED IN ND 1002246. A LEAKAGE RATE OF 5 x 10<sup>-8</sup> cc/atm/sec OR GREATER

D. AVERAGE PROPAGATION DELAY  $(T_p)$ : MEASUREMENTS SHALL BE PERFORMED ON EACH INPUT USING TEST CIRCUIT SPECIFIED IN FIGURE 1 MADE UP OF ACCEPTABLE UNITS WHERE  $T_p = (T_1 + T_2)/2$ . VOLTAGE 4V ± 10% DURING TEST ALL UNUSED BASES SHALL BE GROUNDED.



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NOTICE - WHEN GOVERNMENT DRAWINGS, SPECIFICATIONS, OR OTHER DAT ARE USED FOR ANY PURPOSE OTHER THAN IN CONNECTION WITH A DEFINITELY RELATED GOVERNMENT PROCUREMENT OPERATION, THE UNITED STATES GOV ERNMENT THEREBY INCURS NO RESPONSIBILITY NOR ANY OBLIGATION WHATSO OTHER DATA IS NOT TO BE REGARDED BY IMPLICATION OR OTHERWISE AS II ANY MANNER LICENSING THE HOLDER OR ANY OTHER PERSON OR CORPORATION OR CONVEYING ANY RIGHTS OR PERMISSION TO MANUFACTURE, USE, OR SELL ANY PATENTED INVENTION THAT MAY IN ANY WAY BE RELATED THERETO. F. VISUAL AND MECHANICAL EXTERNAL EXAMINATION: 4.8 CHANGE IN BETA OF ±10%. TABLE I PRE SEAL VISUAL INSPECTION TEST CONDITIONS TEST A State of the sta SEE NOTE 2C(2) VISUAL AND 4G INTERNAL INSPECTION Contraction of the second s

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# TABLE II

ACCEPTANCE INSPECTION **										
SYMBOL		TEST CO	ONDITION	S		<u></u>	LIMI	TS	UNITS	LOT
					• · · · · · · · · · · · · · · · · · ·		MIN	MAX		
-	METHOD 2071 SEE NOTE 3 [	) (6)					-	-		*LTPD = 10 MAX. ACC. NO. = 3
	PIN 2,6	PIN 3,7	PIN 5	PIN 4,8	PIN 1,9	PIN 10		4.5.2		
B B B B	+870+2mV +1800±10mV +1800±10mV	+1800±10mV +870±2mV +1800±10mV	OV OV OV	+1800±10mV +1800±10mV +870±2mV		+4±.01V +4±.C1V +4±.01V		152 152 152	uA uA uA	MAX. ACC. NO. 2 (COMBINED)
Vo Vo Vo	+770±2mV OPEN OPEN	OPEN +770±2mV OPEN	0V 0V 0V	OPEN OPEN +770±2mV		+4±.01V +4±.01V +4±.01V		300 300 300	mV mV mV	
V <sub>S</sub> V <sub>S</sub> V <sub>S</sub>	+870±2mV OPEN OPEN	OPEN +870±2mV OPEN	0V 0V 0V	OPEN OPEN +870±2mV		+4±.01V +4±.01V +4±.01V		220 220 220	mV mV mV	*LTPD = 5 (COMBINED) MAX, ACC, NO, = 3
10 ICEX	+500±2mV +500±2mV	+500±2mV +500±2MV	0V 0V	+500±2mV +500±2mV	+870±2mV +1,00±.01V	+4±.01V OPEN	760	15	uA uA	
I CEO 1 EBO I CBO	OPEN OV OV	OPEN OV OV	0V +4±.1V OPEN	OPEN OV OV	+5±.1V OPEN +8±.1V	OPEN OPEN OPEN		100 100 100	uA uA uA	
B <sub>1</sub>	870±2mV	OPEN	OV	OPEN	5KN TO +10V	OPEN		400	mV	
B <sub>2</sub>	OPEN	870±2mV	OV	OPEN	5KΩ TO +10V	OPEN		400	mV	
B3	OPEN	OPEN	OV	870±2mV	5 KΩ TO +10V	OPEN		400	mV	
VCEO SUST.	$l_{\rm C} = 5 {\rm mA}$	(PULSED) PI	NS 1,9 A	ND 5			5		VOLTS	5
Гр	SEE NOTE 3D (4) AND FIGURE 1				- -		24	nsec	*LIPD = 7 MAX.ACC.NO. = 1	
RL	BETWEEN PINS 10 AND 1,9 MEASUREMENT CURRENT = $1mA$						2.7	4.15	Kohm	*LTPD = 10 5 MAX.ACC.NO. = 3
hFE	$l_{\rm C} = 1$ mA	$V_{CE} = 0.5V$	ALL TR	ANSISTORS			30	200		$\frac{*LTPD = 7}{MAX \cdot ACC \cdot NO = 1}$

 LTPD PER MIL-S-19500C, TABLE IV
 \*\* SAMPLE SIZE USED BY THE BUYER AND VENDOR SHALL BE THE SAME AND SHALL CORRESPOND TO THE MAX ACC NUMBER SPECIFIED IN MIL-S-19500C, TABLE IV
 \*\*\* MEASUREMENTS TO BE MADE ON GATE 1 AND GATE 2.
 \*\*\* TEKTRONIX SAMPLING PROBE P6032 WITH 50X ATTENUATOR
 \*\*\*\* TEST TO BE PERFORMED IN SEQUENCE INDICATED

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	TABLE III .	
	QUALITY DEMONSTRATION TESTS**	
	TEST CONDITION	LOT
	SEE NOTE 2 D(3) METHOD 2066	LTPD* = 20 MAX.ACC.NO.=1
	SEE NOTE 2 D(4) METHOD 1056, CONDITION B (150°C TO -65°C, 5 CYCLES) SEE NOTE 4 C	LTPD* = 7 (COMBINED) MAX.ACC.NO.=1
ON	SEE NOTE 2D(4) METHOD 1031 tstg = 150 ± 5°C, 1000 HOURS METHOD 2016, 1500 G, 0.5 MSEC 5 BLOWS EACH IN ALL AXIS DIRECTIONS 30 BLOWS TOTAL METHOD 2056, 30 G FROM 5 TO 2000 CPS LIMITED TO 0.12 DOUBLE AMPLITUDE, 3 CYCLES, 15 MINUTES PER CYCLE MINIMUM METHOD 2006, (20,000 G) Y1 & Y2 AXIS ONLY	LTPD* = 5 (COMBINED) MAX.ACC.NO.= 1
	SEE NOTE 2 D (4) METHOD 1026 SEE NOTE 4 E AND FIGURE 2 $T_A = +22$ °C MIN IN FREE AMBIENT AIR t = 1000 HOURS	<b>h</b> * = 3 MAX. ACC. NQ = 0
	SEE NOTE 2D(3) SEE NOTE 4A SEE NOTE 4B	LTPD* = 20 (COMBINED) MAX.ACC.NO.=1
-		•
	SEE NOTE 4H (8) AND NOTE 2 D(5) t = 72 HOURS TA = $100 \pm 5^{\circ}C$	LTPD* = 15 MAX.ACC.NO=2

FIGURE 2 TEST CIRCUIT - POWER BURN

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•	APPLIC	ATION

END <u>SU</u> OUT

![](_page_4_Figure_10.jpeg)

TEST	SYMBOL	CONDITIONS	LIMI MIN	МАХ	UNITS
END POINTS FOR SUBGROUPS 2 3 4 AND 6		•			
OUTPUT VOLTAGE, PIN 1,9 OUTPUT VOLTAGE, PIN 1,9 OUTPUT VOLTAGE, PIN 1,9 OUTPUT CURRENT, PIN 1,9	VO VO VO IO	SAME AS SPECIFIED IN TABLE II	- - 760	300 300 300 -	mV mV mV
COLLECTOR EMITTER THRESHOLD CURRENT	I CEX		-	20	uA
BASE CURRENT, 1 2,6 BASE CURRENT, 1 3,7 BASE CURRENT, 1 4,8	B B B		-	152 152 152	uA uA uA

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DIMENSIONS ARE IN INCHES	INSTRUMENTATION LAB CAMBRIDGE, MASS. DWS. NO. CONTRACT	M	
FRACTIONS     DECIMALS     ANGLES $\pm$ $\pm$ $\pm$ $\pm$ DO     NOT     SCALE     THIS     DRAWING	DRAWN J. addoren DATEZZDEC64 CHECKED & Hanky APPROVAL & Hanley APPROVAL & Hanley APPROVAL & Hanley APPROVAL & Hanley	DL (	JA (F
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